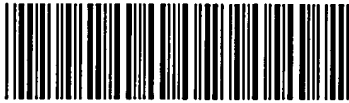


Search Notes

Application/Control No.

10/662,826

Examiner

Jia W. Lu

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	346	11/17/2006	JL
455	278.1	11/17/2006	JL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	346	11/17/2006	JL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
all east databases	11/17/2006	JL
IEEE Xplore	11/17/2006	JL
Inventorship	11/17/2006	JL